

### FEATURES

**Ultralow Offset Voltage:**  $10\mu\text{V}$   
**Ultralow Offset Voltage Drift:**  $0.2\mu\text{V}/^\circ\text{C}$   
**Ultrastable vs. Time:**  $0.2\mu\text{V}/^\circ\text{C}$   
**Ultralow Noise:**  $0.35\mu\text{V p-p}$   
**No External Components Required**  
**Monolithic Construction**  
**High Common-Mode Input Range:**  $\pm 14.0\text{V}$   
**Wide Power Supply Voltage Range:**  $\pm 3\text{V}$  to  $\pm 18\text{V}$   
**Fits 725, 108A/308A Sockets**  
**Military Parts and Plus Parts Available**  
**8-Pin Plastic Mini-DIP, Cerdip, TO-99 Hermetic Metal Can, or SOIC**  
**Available in Wafer-Trimmed Chip Form**  
**Available in Tape and Reel in Accordance with EIA-481A Standard**  
**Surface Mount (SOIC)**

### PRODUCT DESCRIPTION

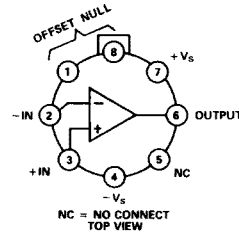
A guaranteed minimum open-loop voltage gain of 3,000,000 (AD OP-07A) represents an order of magnitude improvement over older designs; this affords increased accuracy in high closed-loop gain applications. Typical input offset voltages as low as  $10\mu\text{V}$ , typical bias currents of  $0.7\text{nA}$ , internal compensation and device protection eliminate the need for external components and adjustments. An input offset voltage temperature coefficient of  $0.2\mu\text{V}/^\circ\text{C}$  (typ) and long-term stability of  $0.2\mu\text{V}/\text{month}$  (typ) eliminate recalibration or loss of initial accuracy.

A true differential operational amplifier, the AD OP-07 has a high common-mode input voltage range ( $\pm 13\text{V}$  min) common-mode rejection ratio (typically up to 126dB) and high differential input impedance ( $50\text{M}\Omega$  typ); these features combine to assure high accuracy in noninverting configurations. Such applications include instrumentation amplifiers where the increased open-loop gain maintains high linearity at high closed-loop gains.

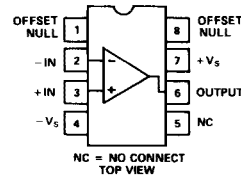
The AD OP-07 is available in five performance grades. The AD OP-07E, AD OP-07C and AD OP-07D are specified for operation over the  $0$  to  $+70^\circ\text{C}$  temperature range, while the AD OP-07A and AD OP-07 are specified for  $-55^\circ\text{C}$  to  $+125^\circ\text{C}$  operation. All devices are available in either the TO-99 hermetically sealed metal cans or the hermetically sealed cerdip packages, while the commercial grades are also available in plastic 8-pin mini-DIP and plastic surface mount (SOIC) packages.

### CONNECTION DIAGRAMS

#### TO-99 (H) Package



#### Plastic Mini-DIP (N), Cerdip (Q) and SOIC (R) Packages



### PRODUCT HIGHLIGHTS

1. Increased open-loop voltage gain (3.0 million min) results in better accuracy and linearity in high closed-loop gain applications.
2. Ultralow offset voltage and offset voltage drift, combined with low input bias currents, allow the AD OP-07 to maintain high accuracy over the entire operating temperature range.
3. Internal frequency compensation, ultralow input offset voltage and full device protection eliminate the need for additional components. This reduces circuit size and complexity and increases reliability.
4. High input impedances, large common-mode input voltage range and high common-mode rejection ratio make the AD OP-07 ideal for noninverting and differential instrumentation applications.
5. Monolithic construction along with advanced circuit design and processing techniques result in low cost.
6. The input offset voltage is trimmed at the wafer stage. Unmounted chips are available for hybrid circuit applications.

# AD OP-07 — SPECIFICATIONS ( $T_A = +25^\circ\text{C}$ , $V_S = \pm 15\text{ V}$ , unless otherwise specified)

Model Parameter	Symbol	AD OP-07E			AD OP-07C			AD OP-07D		
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max
OPEN LOOP GAIN	$A_{VO}$	2,000 1,800 300	5,000 4,500 1,000		1,200 1,000 300	4,000 4,000 1,000		1,200 1,000 300	4,000 4,000 1,000	
OUTPUT CHARACTERISTICS										
Maximum Output Swing	$V_{OM}$	$\pm 12.5$ $\pm 12.0$ $\pm 10.5$ $\pm 12.0$	$+ 13.0$ $+ 12.8$ $+ 12.0$ $+ 12.6$		$\pm 12.0$ $\pm 11.5$	$+ 13.0$ $+ 12.8$ $+ 12.0$ $+ 12.6$		$\pm 12.0$ $\pm 11.5$	$+ 13.0$ $+ 12.8$	
Open-Loop Output Resistance	$R_{O}$		60			60			60	
FREQUENCY RESPONSE										
Closed Loop Bandwidth	BW		0.6			0.6			0.6	
Slew Rate	SR		0.17			0.17			0.17	
INPUT OFFSET VOLTAGE										
Initial	$V_{OS}$		30 45	75 130		60 85 150 250			60 85 150 250	
Adjustment Range			$\pm 4$			$\pm 4$			$\pm 4$	
Average Drift										
No External Trim	$TCV_{OS}$		0.3	1.3		0.5 1.8			0.7 2.5	
With External Trim	$TCV_{OSN}$		0.3	1.3		0.4 1.6			0.7 2.5	
Long Term Stability	$V_{OS}/\text{Time}$		0.3	1.5		0.4 2.0			0.5 3.0	
INPUT OFFSET CURRENT										
Initial	$I_{OS}$		0.5 0.9	3.8 5.3		0.8 1.6 6.0 8.0			0.8 1.6 6.0 8.0	
Average Drift	$TCI_{OS}$		8	35		12 50			12 50	
INPUT BIAS CURRENT										
Initial	$I_B$		$\pm 1.2$ $\pm 1.5$	$\pm 4.0$ $\pm 5.5$		$\pm 1.8$ $\pm 2.2$ $\pm 7.0$ $\pm 9.0$			$\pm 2.0$ $\pm 3.0$ $\pm 12$ $\pm 14$	
Average Drift	$TCI_B$		13	35		18 50			18 50	
INPUT RESISTANCE										
Differential	$R_{IN}$	15	50		8	33		7	31	
Common Mode	$R_{INCM}$		160			120			120	
INPUT NOISE										
Voltage	$e_n\text{ p-p}$		0.35	0.6		0.38 0.65			0.38 0.65	
Voltage Density	$e_n$		10.3 10.0 9.6	18.0 13.0 11.0		10.5 10.2 9.8 11.5			10.5 10.2 9.8 11.5	
Current	$i_n\text{ p-p}$		14	30		15 35			15 35	
Current Density	$i_n$		0.32 0.14 0.12	0.80 0.23 0.17		0.35 0.15 0.13 0.18			0.35 0.15 0.13 0.18	
INPUT VOLTAGE RANGE										
Common Mode	CMVR	$\pm 13.0$ $\pm 13.0$	$\pm 14.0$ $\pm 13.5$		$\pm 13.0$ $\pm 13.0$	$\pm 14.0$ $\pm 13.5$		$\pm 13.0$ $\pm 13.0$	$\pm 14.0$ $\pm 13.5$	
Common-Mode Rejection Ratio	CMRR	106 103	123 123		100 97	120 120		94 94	110 106	
POWER SUPPLY										
Current, Quiescent	$I_Q$		3.0	4.0		3.5 5.0			3.5 5.0	
Power Consumption	$P_D$		90 6.0	120 9.0		105 6.0 9.0			105 6.0 9.0	
Rejection Ratio	PSRR	94 90	107 104		90 86	104 100		90 86	104 100	
OPERATING TEMPERATURE RANGE	$T_{min}$ , $T_{max}$	0		$+ 70$	0		$+ 70$	0		$+ 70$

## NOTES

<sup>1</sup>Input Offset Voltage measurements are performed by automated test equipment approximately 0.5 seconds after application of power. Additionally, the AD OP-07A offset voltage is guaranteed fully warmed up.

<sup>2</sup>Long-Term Input Offset Voltage Stability refers to the averaged trend line of  $V_{OS}$  vs. Time over extended periods of time and is extrapolated from high temperature test data. Excluding the initial hour of operation, changes in  $V_{OS}$  during the first 30 operating days are typically  $2.5\mu\text{V}$  - Parameter is not 100% tested; 90% of units meet this specification.

Specifications subject to change without notice.

AD OP-07A			AD OP-07			Test Conditions	Units
Min	Typ	Max	Min	Typ	Max		
<b>3,000</b>	5,000		<b>2,000</b>	5,000		$R_i \geq 2k\Omega, V_{O1} = \pm 10V$	V/mV
<b>2,000</b>	4,000		<b>1,500</b>	4,000		$R_i \geq 2k\Omega, V_{O1} = \pm 10V, T_{min} \text{ to } T_{max}$	V/mV
300	1,000		300	1,000		$R_i = 500\Omega, V_{O1} = \pm 0.5V, V_S = \pm 3V$	V/mV
$\pm 12.5$	$\pm 13.0$		$\pm 12.5$	$\pm 13.0$		$R_i \geq 10k\Omega$	V
$\pm 12.0$	$\pm 12.8$		$\pm 12.0$	$\pm 12.8$		$R_i \geq 2k\Omega$	V
$\pm 10.5$	$\pm 12.0$		$\pm 10.5$	$\pm 12.0$		$R_i \geq 1k\Omega$	V
$\pm 12.0$	$\pm 12.6$		$\pm 12.0$	$\pm 12.6$		$R_i \geq 2k\Omega, T_{min} \text{ to } T_{max}$	V
60			60			$V_{O1} = 0, I_{O1} = 0$	$\Omega$
0.6			0.6			$A_{V_{CL}} = +1.0$	MHz
0.17			0.17			$R_i \geq 2k$	V/ $\mu s$
10	25		30	75		Note 1	$\mu V$
25	<b>60<sup>1</sup></b>		60	<b>200<sup>1</sup></b>		$T_{min} \text{ to } T_{max}$	$\mu V$
$\pm 4$			$\pm 4$			$R_p = 20k\Omega$	mV
0.2	<b>0.6</b>		0.3	<b>1.3</b>		$T_{min} \text{ to } T_{max}$	$\mu V/^\circ C$
0.2	0.6		0.3	1.3		$R_p = 20k\Omega, T_{min} \text{ to } T_{max}$	$\mu V/^\circ C$
0.2	1.0		0.2	1.0		Note 2	$\mu V/\text{Month}$
0.3	<b>2.0</b>		0.4	<b>2.8</b>		$T_{min} \text{ to } T_{max}$	nA
0.8	<b>4.0</b>		1.2	<b>5.6</b>		$T_{min} \text{ to } T_{max}$	nA
5	25		8	50		$T_{min} \text{ to } T_{max}$	pA/^\circ C
$\pm 0.7$	$\pm 2.0$		$\pm 1.0$	$\pm 3.0$		$T_{min} \text{ to } T_{max}$	nA
$\pm 1.0$	$\pm 4.0$		$\pm 2.0$	$\pm 6.0$		$T_{min} \text{ to } T_{max}$	nA
8	25		13	50		$T_{min} \text{ to } T_{max}$	pA/^\circ C
30	80		20	60			M $\Omega$
	200			200			G $\Omega$
0.35	0.6		0.35	0.6		0.1Hz to 10Hz	$\mu V \text{ p-p}$
10.3	18.0		10.3	18.0		$f_{O1} = 10Hz$	nV/ $\sqrt{Hz}$
10.0	13.0		10.0	13.0		$f_{O1} = 100Hz$	nV/ $\sqrt{Hz}$
9.6	11.0		9.6	11.0		$f_{O1} = 1kHz$	nV/ $\sqrt{Hz}$
14	30		14	30		0.1Hz to 10Hz	pA p-p
0.32	0.80		0.32	0.80		$f_{O1} = 10Hz$	pA/ $\sqrt{Hz}$
0.14	0.23		0.14	0.23		$f_{O1} = 100Hz$	pA/ $\sqrt{Hz}$
0.12	0.17		0.12	0.17		$f_{O1} = 1kHz$	pA/ $\sqrt{Hz}$
$\pm 13.0$	$\pm 14.0$		$\pm 13.0$	$\pm 14.0$		$T_{min} \text{ to } T_{max}$	V
$\pm 13.0$	$\pm 13.5$		$\pm 13.0$	$\pm 13.5$			V
<b>110</b>	126		<b>110</b>	126		$V_{CM} = \pm CMVR$	dB
<b>106</b>	123		<b>106</b>	123		$V_{CM} = \pm CMVR, T_{min} \text{ to } T_{max}$	dB
3.0	<b>4.0</b>		30	<b>4.0</b>		$V_S = \pm 15V$	mA
90	<b>120</b>		90	<b>120</b>		$V_S = \pm 15V$	mW
6.0	<b>8.4</b>		6.0	<b>8.4</b>		$V_S = \pm 3V$	mW
<b>100</b>	110		<b>100</b>	110		$V_S = \pm 3V \text{ to } \pm 18V$	dB
<b>94</b>	106		<b>94</b>	106		$V_S = \pm 3V \text{ to } \pm 18V, T_{min} \text{ to } T_{max}$	dB
-55	+125		-55	+125			^\circ C

Specifications shown in boldface are tested on all production units at final electrical test. Results from those tests are used to calculate outgoing quality levels. All min and max specifications are guaranteed, although only those shown in boldface are tested on all production units.

# AD OP-07

## ABSOLUTE MAXIMUM RATINGS

Supply Voltage	± 22V
Internal Power Dissipation (Note 1)	500mW
Differential Input Voltage	± 30V
Input Voltage	± V <sub>S</sub>
Output Short Circuit Duration	Indefinite
Storage Temperature Range	- 65°C to + 150°C
Operating Temperature Range	
AD OP-07A, AD OP-07	- 55°C to + 125°C
AD OP-07E, AD OP-07C, AD OP-07D	0 to + 70°C
Lead Temperature Range (Soldering 60sec)	+ 300°C

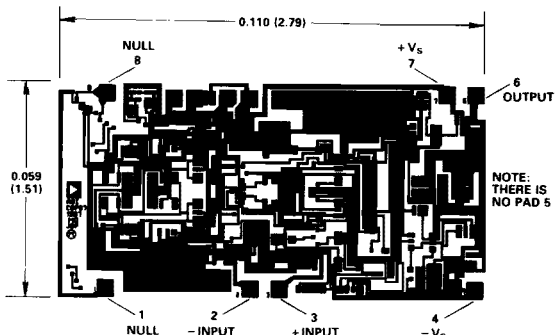
### NOTE

Note 1: Maximum package power dissipation vs. ambient temperature.

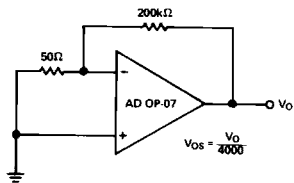
Package Type	Maximum Ambient Temperature for Rating	Derate Above Maximum Ambient Temperature
TO-99 (H)	80°C	7.1mW/°C
Mini-DIP (N)	36°C	5.6mW/°C
Cerdip (Q)	75°C	6.7mW/°C

## CHIP DIMENSIONS AND BONDING DIAGRAM

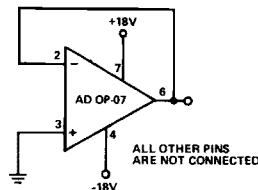
Dimensions shown in inches and (mm).  
Contact factory for latest dimensions.



THE AD OP-07 IS AVAILABLE IN WAFER-TRIMMED CHIP FORM FOR PRECISION HYBRIDS. CONSULT THE FACTORY FOR DETAILS.



Offset Voltage Test Circuit



Burn-In Circuit

## ORDERING GUIDE<sup>1</sup>

Model	Temperature Range (°C)	Max Initial Offset (μV)	Max Offset Drift (μV/°C)	Package Description	Package Option <sup>2</sup>
ADOP-07EH	0 to +70	75	1.3	TO-99	H-08A
ADOP-07EN	0 to +70	75	1.3	Mini-DIP	N-8
ADOP-07EQ	0 to +70	75	1.3	Cerdip	Q-8
ADOP-07CH	0 to +70	150	1.8	TO-99	H-08A
ADOP-07CN	0 to +70	150	1.8	Mini-DIP	N-8
ADOP-07CQ	0 to +70	150	1.8	Cerdip	Q-8
ADOP-07CR	0 to +70	150	1.8	SOIC	R-8
ADOP-07CR-REEL	0 to +70	150	1.8	SOIC	
ADOP-07DH	0 to +70	150	2.5	TO-99	H-08A
ADOP-07DN	0 to +70	150	2.5	Mini-DIP	N-8
ADOP-07DQ	0 to +70	150	2.5	Cerdip	Q-8
ADOP-07AH	-55 to +125	25	0.6	TO-99	H-08A
ADOP-07AQ	-55 to +125	25	0.6	Cerdip	Q-8
ADOP-07H	-55 to +125	75	1.3	TO-99	H-08A
ADOP-07Q	-55 to +125	75	1.3	Cerdip	Q-8

### NOTES

<sup>1</sup>A, C and D grade chips are also available.

<sup>2</sup>For outline information see Package Information section.

The AD OP-07 may be directly substituted for other OP-07s as well as 725, 108/208/308, 108A/208A/308A, 714, OP-05 or LM11 devices, with or without removal of external frequency compensation or offset nulling components. If used to replace 741 devices, offset nulling components must be removed (or

referenced to  $+V_S$ ). Input offset voltage of AD OP-07 is very low, but if additional nulling is required, the circuit shown in Figure 1 is recommended.

The AD OP-07 provides stable operation with load capacitances up to 500pF and  $\pm 10V$  swings; larger capacitances should be decoupled with 50 $\Omega$  resistor.

Stray thermoelectric voltages generated by dissimilar metals (thermocouples) at the contacts to the input terminals can prevent realization of the drift performance indicated. Best operation will be obtained when both input contacts are maintained at the same temperature, preferably close to the temperature of the device's package.

Although the AD OP-07 features high power supply rejection, the effects of noise on the power supplies may be minimized by bypassing the power supplies as close to Pins 4 and 7 of the AD OP-07 as possible, to load ground with a good-quality 0.01 $\mu F$  ceramic capacitor as shown in Figure 1.

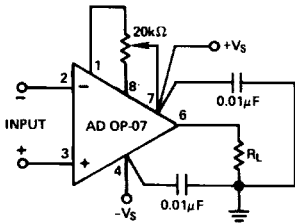
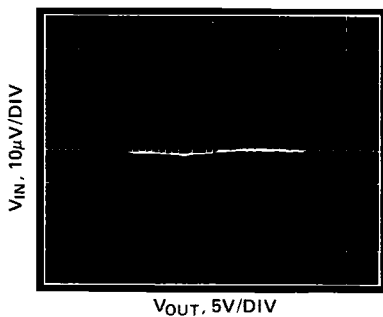
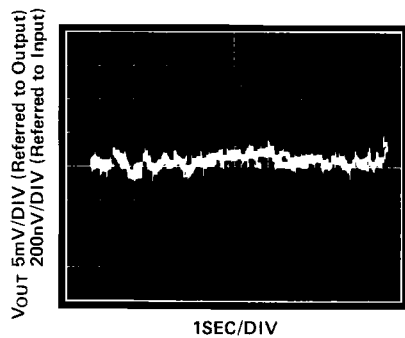


Figure 1. Optional Offset Nulling Circuit and Power Supply Bypassing

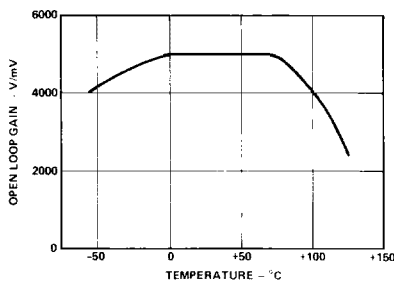
## Performance Curves (typical @ $T_A = +25^\circ C$ , $V_S = \pm 15V$ , AD OP-07 Grade Device unless otherwise noted)



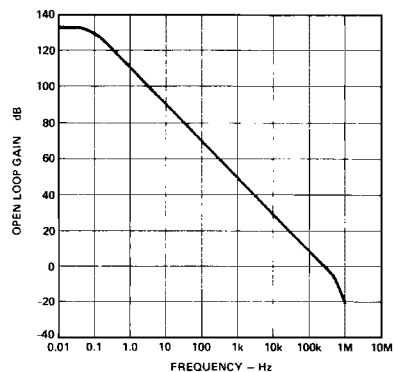
AD OP-07 Open-Loop Gain Curve



AD OP-07 Low Frequency Noise (See Test Circuit, on the Previous Page)

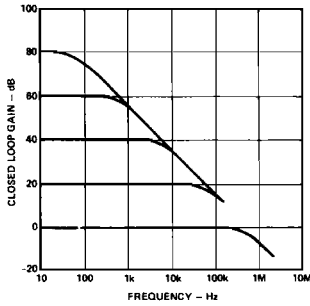


Open-Loop Gain vs. Temperature

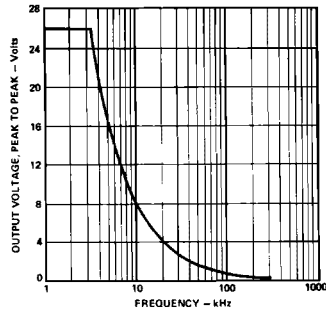


Open-Loop Frequency Response

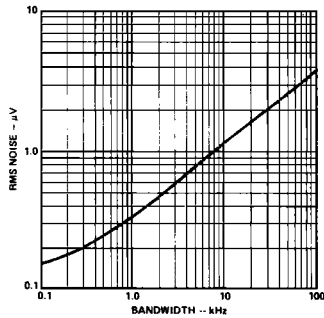
# AD OP-07—Typical Performance Curves



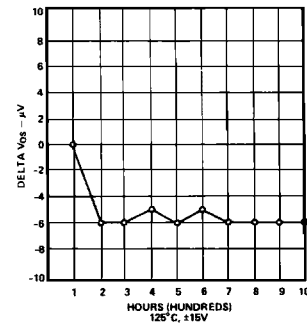
*Closed-Loop Response for Various Gain Configurations*



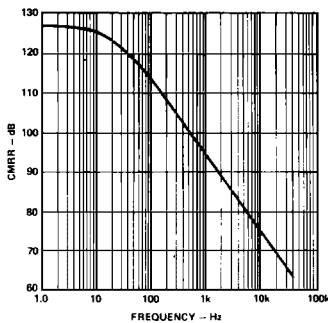
*Maximum Undistorted Output vs. Frequency*



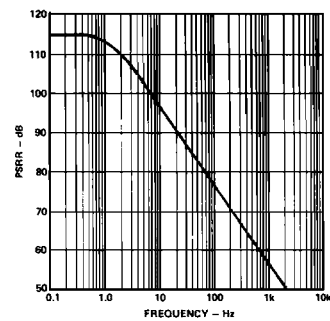
*Input Wideband Noise vs. Bandwidth (0.1kHz to Frequency Indicated)*



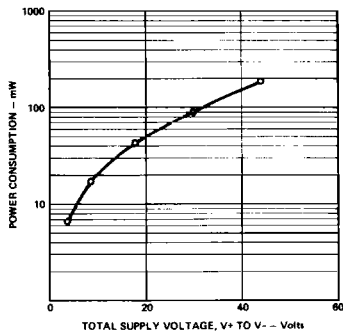
*Offset Voltage vs. Time*



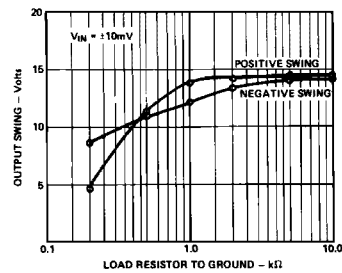
*CMRR vs. Frequency*



*PSRR vs. Frequency*



*Power Consumption vs. Power Supply*



*Output Voltage vs. Load Resistance*